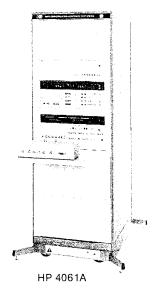


COMPONENT & SEMICONDUCTOR MEASUREMENT

Semiconductor/Component Test System Model 4061A

- Ready to use—supplied with 7 turn-key application
- Reliable impedance and current measurements with one probing
- · Productivity improvement through accurate and fast measurement over wide range





Description

The HP 4061A Semiconductor/Component Test System is a dedicated system for making efficient, automatic evaluation of the fundamental characteristics of semiconductor and electronic components required in R & D and production areas. This system employs reliable, accurate measurements and high speed data processing to perform more reliable evaluations with speed and less manpower. The HP 4061A is supplied with 7 sophisticated applications programs and is flexible in both software and hardware. Thus, the system can output measurement results in nearly any required data format.

The switching subsystem, designed especially for use with the HP 4061A, allows both impedance and current measurement without changing DUT connection. Using this new switching subsystem, and by making impedance measurements, the HP 4061A performs evaluation of Doping profile, Oxide capacitance, Flat band condition, Threshold voltage, Surface charge, and Minority carrier life time/surface generation velocity. The HP 4061A also measures leakage current and reverse/forward current-voltage characteristics. Surface state density evaluation, using both high (e.g., 1 MHz) and low frequency (Quasi-static) C-V measurements and data processing are also possible by making modifications to system software.

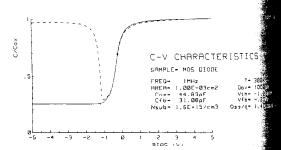
The system offers significant improvement in both yield and quality in production through fast and reliable measurements and evaluations. It is also a valuable evaluation tool for the development of new materials and devices. The HP 4061A provides the flexibility to meet the future measurement requirements of the electronics industry

System Configuration

HP 4140B pA Meter/DC Voltage Source HP 4275A Multi-frequency LCR Meter Switching Subsystem HP 29402C 56-inch Rack Cabinet

Furnished Application Software

Semiconductor high/low frequency C-V characteristics, I-V characteristics, C-t characteristics and Zerbst analysis, Impedance Frequency/Bias characteristics, Ideal C-V curve.



Specification

For detailed specifications on each of the instruments use HP 4061A, refer to the individual data sheets.

Switching Subsystem

The switching subsystem consists of a switch control module switching module with interconnecting cables.

Function: Switches connection from DUT to either Multi-LCR Meter or the pA Meter/DC Voltage source

System Measurement Range (only deviations from the instrument specifications are listed

Impedance Measurements (HP 4275A)

Frequency range: $\leq 1 \text{ MHz}$ Measurement parameters: C-G Capacitance: $\leq 2000 \text{ pF}$ (with $D \leq 0.1$)

*Accuracy: (accuracy of HP $4\overline{275}$ A) \times 1.5 + Δ C (4)

аC).

 $\Delta C = 1.4 \times 10^{-3} C \times f^2 \ (pF) + 5 \ counts$ Conductance: $\leq 12 mS \ (D \leq 0.1)$

Accuracy: (accuracy of 4275A) \times 1.5 + Δ G (at 23°C)

 $\Delta G = 6 \times 10^{-3} \text{C} \times \text{f(S)} + 5 \text{ counts}$ * f: frequency in MHz

Cx: Measured capacitance value in p

aff latelate

6 restado

diff

2.20m/A

Technical.

100

las MU outp

At 5°C to 40°C, ΔC and ΔG doubles. Example: Assuming 1000 pF and f=1 MHz, $C=(1.4\times10^{-3}\cdot10^3\cdot(1))$ counts=1.4 pF + 5 counts

Current Measurements (HP 4140B)

Accuracy: (accuracy of HP 4140B) \times 1.5 + 5 counts After one-hour warmup and at DUT terminal of switching

Impedance Measuring Section (HP 4275A) See the HP 4275A's page.

Current Measurement Section (HP 4140B)

See the HP 4140B's page.

General Information

Operating temperature: 5°C to 40°C, ≤70%RH at 40° Power: 100, 120, 220, and 240V, +5% to 10%, 48 to 66 Hz, 30 Size: 535mm W x 1635 mm H x 770 mm D (21" x 64.4"), 100 Weight: Approximately 125 kg (275 lbs).

System Controller

HP 9000 Series 200 Model 226A/236A/226S/2368 Technical Computer

Ordering Information

HP 4061A Semiconductor/Component Test Sys-

tem (does not include controller)

Opt. 001: ±100 V dc Bias for HP 4275A

Opt. 002: 1-3-5 Frequency Steps for HP 4275A

Opt. 026*: System library for HP 9826A/S controller

Opt. 036*: System library for HP 9836A/S controller

*Must order either OPT, 026 or 036.

NOTE: Refer to HP 4061A data sheet for details